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- Functionally Equivalent to QS3257
- 5-Ω Switch Connection Between Two Ports
- TTL-Compatible Input Levels
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB, DBQ), and Thin Shrink Small-Outline (PW) Packages

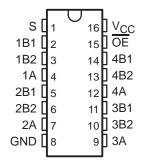
### description

The SN74CBT3257 is a 4-bit 1-of-2 high-speed TTL-compatible FET multiplexer/demultiplexer. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

Output-enable  $(\overline{OE})$  and select-control (S) inputs select the appropriate B1 and B2 outputs for the A-input data.

The SN74CBT3257 is characterized for operation from –40°C to 85°C.

## D, DB, DBQ, OR PW PACKAGE (TOP VIEW)



#### **FUNCTION TABLE**

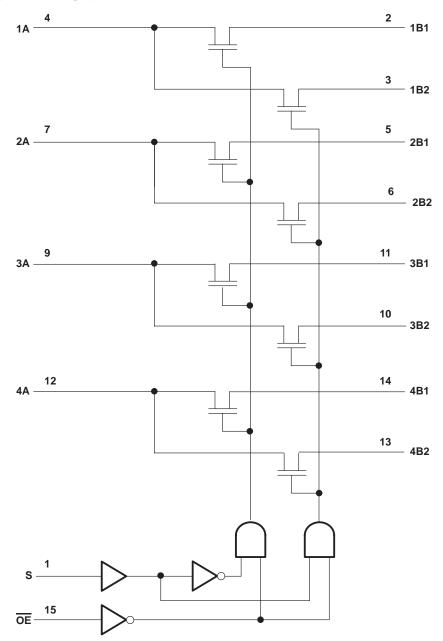
INPUTS		FUNCTION				
OE	S	FUNCTION				
L	L	A port = B1 port				
L	Н	A port = B2 port				
Н	Χ	Disconnect				



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### logic diagram (positive logic)





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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>		–0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		–0.5 V to 7 V
Continuous channel current		128 mA
Input clamp current, $I_K (V_{I/O} < 0)$		50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2	): D package	113°C/W
	DB package	131°C/W
	DBQ package	139°C/W
	PW package	149°C/W
Storage temperature range, T <sub>sto</sub>		65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
VCC	Supply voltage	4	5.5	V
VIH	High-level control input voltage	2		V
V <sub>IL</sub>	Low-level control input voltage		0.8	V
TA	Operating free-air temperature	-40	85	°C

NOTE 3: All unused control inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAR	AMETER		TEST CONDITI	ONS	MIN	TYP‡	MAX	UNIT
VIK		$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA				-1.2	V
lį		$V_{CC} = 5.5 \text{ V},$	$V_I = 5.5 \text{ V or GND}$				±1	μΑ
Icc		$V_{CC} = 5.5 \text{ V},$	I <sub>O</sub> = 0,	$V_I = V_{CC}$ or GND			3	μΑ
∆ICC§	Control inputs	$V_{CC} = 5.5 \text{ V},$	One input at 3.4 V,	Other inputs at V <sub>CC</sub> or GND			2.5	mA
Ci	Control inputs	V <sub>I</sub> = 3 V or 0				3.5		pF
C: (0==)	A port	V <sub>O</sub> = 3 V or 0,	<del></del>			6.5		pF
C <sub>io</sub> (OFF)	B port		OE = VCC			4		þг
		$V_{CC} = 4 \text{ V},$ TYP at $V_{CC} = 4 \text{ V}$	V <sub>I</sub> = 2.4 V,	I <sub>I</sub> = 15 mA		14	20	
$r_{on}\P$		1/4	V <sub>1</sub> = 0	I <sub>I</sub> = 64 mA		5	7	Ω
		V <sub>CC</sub> = 4.5 V	V - 0	$I_I = 30 \text{ mA}$		5	7	
			V <sub>I</sub> = 2.4 V,	I <sub>I</sub> = 15 mA		10	15	

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$  (unless otherwise noted),  $T_A = 25^{\circ}\text{C}$ .



NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51.

<sup>§</sup> This is the increase in supply current for each input that is at the specified TTL voltage level rather than VCC or GND.

<sup>¶</sup> Measured by the voltage drop between the A and the B terminals at the indicated current through the switch. On-state resistance is determined by the lowest voltage of the two (A or B) terminals.

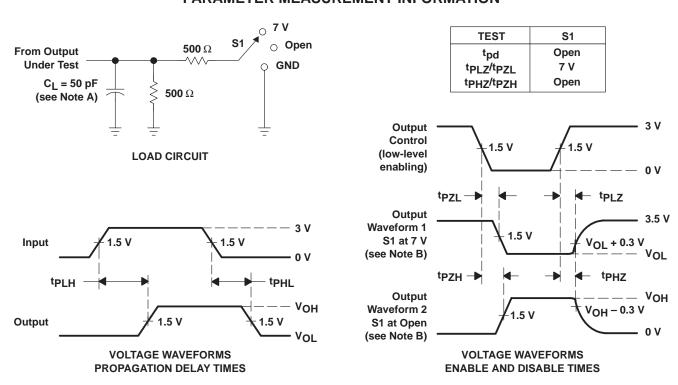
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# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 4 V	V <sub>CC</sub> = 5 \ ± 0.5 V	UNIT
	(INPOT)		MIN MAX	MIN M	ΑX
<sub>tpd</sub> †	A or B	B or A	0.35	0	25 ns
t <sub>pd</sub>	S	A	5.5	1.6	5 ns
<sup>t</sup> en	S	В	5.7	1.6	5.2 ns
	ŌĒ	A or B	5.6	1.8	5.1
<sup>t</sup> dis	S	В	5.2	1	5 ns
	ŌĒ	A or B	5.5	2.2	5.5

<sup>†</sup> The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_r \leq$  2.5 ns,  $t_f \leq$  2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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